

[Fig. 1]

S0 sets the entered slice level to a predetermined one of  $S_k$

S1 measures jitter to produce a measured jitter  
value A

5 S2 increments the slice level in steps of  $S_i$

S3 measures the jitter and produces a measured  
jitter value B

S5 stops the incrementing of the slice level, and measures  
jitter quantity and produces a measured jitter value C

10 S6 decrements the slice level in steps of another fixed  
quantity  $S_d$  ( $< S_i$ )

S7 measures the jitter and produces a measured jitter value  
D

00756726.043004

[Fig. 2]

- A jitter
- B reference slice level
- C slice level

5

[Fig. 4]

- A RF signal
- B binarized signal
- 10 4 RF amplifier
- 5 Decoder
- 6 Microcomputer

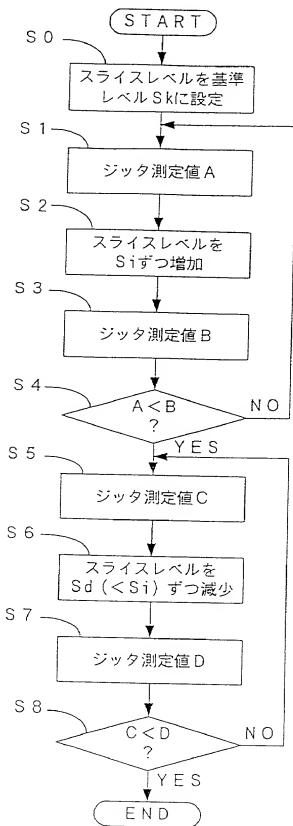
15 [Fig. 5]

- A RF signal
- B binarized signal

【書名】 図面

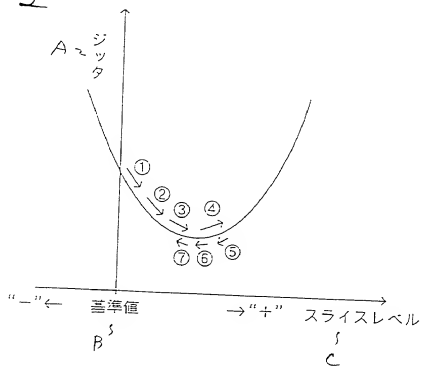
【図 1】

Fig. 1



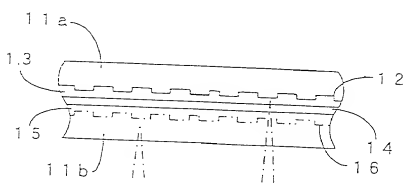
(図 2)

Fig. 2

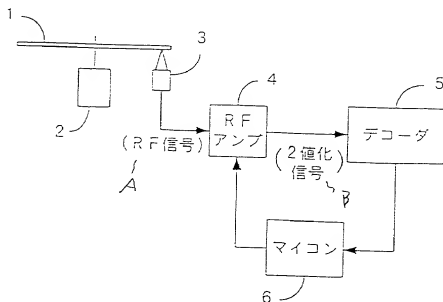


(図 3)

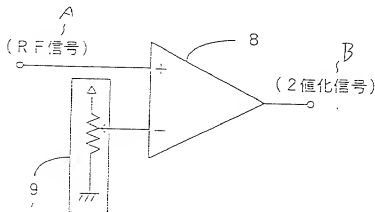
Fig. 3



(図4) Fig. 4



(図5) Fig. 5



(START)

sets the entered slice level to a predetermined one of 52

store A

increments the slice level in steps of 51

store B

A &gt; B?

Y

N

delete A, leave B, store C

increment the slice level

A &gt; C?

Y

N

delete A, leave C, store D

increment the slice level

A &gt; D?

Y

N

delete A, leave C, store D

increment the slice level

B &gt; C?

Y

N

leave B, delete C, store D

increment the slice level

B &gt; D?

Y

N

delete B, leave C, store D

increment the slice level

C &gt; D?

Y

N

set D to be the best value

(END)

Fig. 6

(A, B, C, D : 51 to 52)

